Nomenclature

A	Surface area (m^2), Coefficient used in autoregression analysis (-)
A_B	Gain corresponding to change in bias voltage ($Wm^{-2}sr^{-1}/V$)
A_D	Gain corresponding to change in DAC voltage ($Wm^{-2}sr^{-1}/V$)
A_H	Gain corresponding to change in heatsink temperature ($Wm^{-2}sr^{-1}/K$)
A_S	Gain corresponding to a drift in signal output ($Wm^{-2}sr^{-1}$/count)
A_V	Gain corresponding to change in output signal ($Wm^{-2}sr^{-1}$/count)
B	Thermistor temperature coefficient of resistance (K)
C	Electrical capacitance (μf), Digital-to-Analog conversion factor (409.5 counts/V), Ideal instrument response shape (-)
C_1	Constant used in Planck's radiation distribution function (5.9544×10^8 $W\mu m^4 m^{-2}$)
C_2	Constant used in Planck's radiation distribution function (1.4338×10^4 μmK)
D_{ijk}	Monochromatic radiation distribution factor (-)
e	Emissive power (W)
f	Frequency (Hz)
F	Radiative flux (Wm^{-2})
G	Radiometric gain ($Wm^{-2}sr^{-1}$/count)
I	Electrical current (A), Scene spectral weighting (-)
k	Thermal conductivity ($Wm^{-1}K^{-1}$)

L	Unfiltered radiance ($Wm^{-2}sr^{-1}$)
$\tilde{L}$	Filtered radiance ($Wm^{-2}sr^{-1}$)
m	Instrument output (counts), Number of discretized wavelength intervals (-)
n	Number of surfaces in an enclosure (-)
o	Zero-radiance scan dependent offset (counts)
p	Optical point spread function (-), Power (W), Coefficient in slow mode filtering algorithm (-)
Q	Power (W)
R	Angular dependence model (-), Electrical resistance (Ω), Responsivity (VW^{-1}), Nondimensional response (-)
S	Spectral response (-)
t	Time (s)
T	Temperature (K)
u	Normalized ideal first-order instrument response (-)
v	Normalized slow mode instrument response (-)
V_{bias}	Instrument bridge bias voltage (V)
V_D	Digital-to-Analog converter voltage (V)
w	Normalized measured instrument response (-)

Greek

α	Absorptivity (-)
ε	Emissivity (-)
ϕ	Azimuthal angle (rad)
η	Elevation scan angle (deg)
κ	Magnitude of slow mode (%)
λ	Wavelength (μm), Characteristic time of slow response mode (s^{-1})

λ_{corr} Spectral correction factor (-)

π Pi (3.14159)

θ Zenith angle (rad)

ρ Reflectivity (-)

σ Variance of recovered radiance ($Wm^{-2}sr^{-1}$)

τ Time constant (ms), Time lag between instrument optical axis and centroid of the instrument point spread function (s),Transmittance (-)

Ω Field-of-view solid angle (sr)

ξ Elevation cross-scan angle (deg)

Ψ Point spread function centroid (deg)